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PATENT  
8053-1016

IN THE U.S. PATENT AND TRADEMARK OFFICE

In re application of:

Kazuhiro NAKAJIMA et al.

Conf.: 9942

Appl. No.: 10/625,695

Group: 2811

Filed: July 24, 2003

Examiner: Ori Nadav

For: PRODUCTION PROCESS FOR PRODUCING  
SEMICONDUCTOR DEVICES, SEMICONDUCTOR DEVICES  
PRODUCED THEREBY, AND TEST SYSTEM FOR  
CARRYING OUT YIELD-RATE TEST IN  
PRODUCTION OF SUCH SEMICONDUCTOR DEVICES

AMENDMENT

Assistant Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450  
Sir:

October 19, 2004

In response to the Office Action mailed September 23,  
2004, please amend the above-identified application as follows:

**Amendments to the Claims** are reflected in the listing  
of claims which begins on page 2 of this paper.

**Remarks** begin on page 5 of this paper.